



Product/Process Change Notice - PCN 22_0003 Rev. -

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This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title: ADIS16465 / ADIS16467 Assembly Change Optimization and Data Sheet Revision

Publication Date: 03-Aug-2022

Effectivity Date: 05-Nov-2022 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:

Initial Release.

Description Of Change:

1. Addition of underfill to internal Gyro Sensors.

2. Data Sheet updates from Rev C to Rev D as follows:

-Linear Acceleration Effect Typical Specification improved from 0.009 deg/sec/g to 0.003 deg/sec/g

-Nonlinearity Typical specs broken out from previously only across Full Scale Range (FSR) into FSR and +/- 25% of FSR.

Reason For Change:

Addition of underfill around the Internal Gyroscope sensors provides better stability to reduce Gyroscope bias anomalies and shifts across temperature.

Impact of the change (positive or negative) on fit, form, function & reliability:

No change to form, fit or reliability of the product.

Product Identification *(this section will describe how to identify the changed material)*

Date Code 2248 and greater

Summary of Supporting Information:

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results Summary.

Supporting Documents

Attachment 1: Type: Qualification Results Summary

ADI_PCN_22_0003_Rev_-_ADIS16465 Qualification for Gyro Revision.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

Americas:
PCN_Americas@analog.com

Europe:
PCN_Europe@analog.com

Japan:
PCN_Japan@analog.com

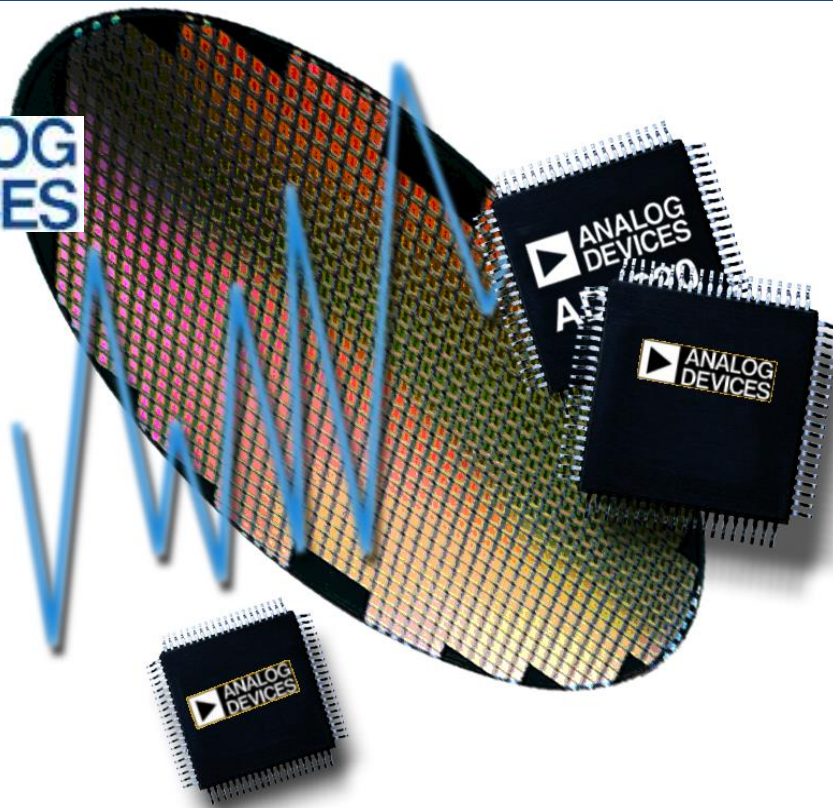
Rest of Asia:
PCN_ROA@analog.com

Appendix A - Affected ADI Models				
Added Parts On This Revision - Product Family / Model Number (6)				
ADIS16465 / ADIS16465-1BMLZ	ADIS16465 / ADIS16465-2BMLZ	ADIS16465 / ADIS16465-3BMLZ	ADIS16467 / ADIS16467-1BMLZ	ADIS16467 / ADIS16467-2BMLZ
ADIS16467 / ADIS16467-3BMLZ				

Appendix B - Revision History			
Rev	Publish Date	Effectivity Date	Rev Description
Rev. -	03-Aug-2022	05-Nov-2022	Initial Release.

Analog Devices, Inc.

DocId:8771 Parent DocId:None Layout Rev:8



Reliability Report

Report Title:	ADIS16465 Gyroscope Revision Qualification
Report Number:	17227
Revision:	A
Date:	2 February 2022

Summary

This report documents the successful completion of the reliability qualification requirements for the release of the ADIS16465 with a gyroscope revision. The ADIS16465 is a precision, microelectric mechanical system (MEMS), inertial measurement unit (IMU) that includes a triaxial gyroscope and a triaxial accelerometer. The gyroscope revision was made for performance improvement and there is no change in reliability. This report also covers the ADIS16467 that has the same product characteristics shown in Table 1. Three gyro range options are included, 125 dps (-1); 500dps (-2); 2000dps (-3). This qualification report covers the following models:

- ADIS16465-1BMLZ
- ADIS16465-2BMLZ
- ADIS16465-3BMLZ
- ADIS16467-1BMLZ
- ADIS16467-2BMLZ
- ADIS16467-3BMLZ

Table 1: ADIS16465 Product Characteristics

Package	14-MCML
Body Size (mm)	24.30 x 22.40 x 9.00
Assembly Location	IMI
SMT Solder	SAC305
Underfill	Hysol FP4545FC
Adhesives	Loctite 3563
Lead Finish	Gold
Gyro Core	Process Codes: 0.18D2L5M40.5018 & MEMS0WL1M00.B1Q & CAP1_WL.A2Q Fab Site: E_TSMC8B08, I_WILM1B06
Accelerometer Core	Process Codes: 0.18C2L5M33.18, CAP1_WL.B1Q, & MEMS0WL1M00.B1Q. Fab Sites: E_TSMC0408, I_WILM1B06

Description / Results of Tests Performed

Table 2 provides a description of the qualification tests conducted and the associated test results for products manufactured on the same technologies as described in Table 1. Table 3 provides data from qualification tests on product containing previous revisions of the gyroscope. All devices were electrically tested before and after each stress. Any device that did not meet all electrical data sheet limits following stressing would be considered a valid (stress-attributable) failure unless there was conclusive evidence to indicate otherwise.

Table 2: Qualification Test Results

Test Name	Specification	Conditions	Device	Lot #	Sample Size	Qty. Failures
Temperature Cycling (TC)	JESD22-A104	-40°C/+105°C, 1000 Cycles	ADIS16465	Q17227.1.2	32	0
Temperature Humidity Bias (THB)	JESD22-A101	85°C, 85%RH, Biased, 1,000 Hours	ADIS16465	Q17227.1.1	16	0

Table 3: Qualification Extension Data*

Test Name	Specification	Conditions	Device	Lot #	Sample Size	Qty. Failures
Temperature Cycle	JESD22-A104	-40°C/+105°C, 500 Cycles	ADIS16465	Q16167.2	16	0
				Q16803.1	16	0
		-40°C/+85°C, 500 cycles	ADIS16465	10191913	16	0
High Temperature Operating Life Test (HTOL)	JESD22-A108	+110°C Ta, 500 Hours	ADIS16465	Q16167.1	16	0
				10191913	16	0

* Note: Qualification extension data is from qualification report RQR09975.

Samples of the ADI internal component technologies contained herein are continuously undergoing reliability evaluation as part of the ADI Reliability Monitor Program. Additional qualification data is available on [Analog Devices' web site](#).

Approvals

Reliability Engineer: Scot Solimine

Additional Information

Data sheets and other additional information are available on [Analog Devices' web site](#)